


<b>Search Notes</b>  	<b>Application/Control No.</b>  10565537	<b>Applicant(s)/Patent Under Reexamination</b>  MELKONIAN ET AL.
	<b>Examiner</b>  Taeyoon Kim	<b>Art Unit</b>  1651

SEARCHED			
Class	Subclass	Date	Examiner
435	257.1; 289.1 searched with claim terms (see attached search history)	2/17/2010	TK

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
435	257.1; 289.1 searched with claim terms (see attached search history)	2/17/2010	TK

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